



# **General Multilayer Ceramic Capacitors**



MLCC is an electronic part that temporarily stores an electrical charge and the most prevalent type of capacitor today. New technologies have enabled the MLCC manufacturers to follow the trend dictated by smaller and smaller electronic devices such as Cellular telephones, Computers, DSC, DVC

### **General Features**

- Miniature Size
- Wide Capacitance and Voltage Range
- Tape & Reel for Surface Mount Assembly
- Low ESR

### **Applications**

- General Electronic Circuit

## Part Numbering

CL	<u>10</u>	<u>B</u>	<u> 104</u>	K	<u>B</u>	<u>8</u>	N	N	N	<u>C</u>
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- Samsung Multilayer Ceramic Capacitor
- 2 Size(mm)
- 3 Capacitance Temperature Characteristic
- 4 Nominal Capacitance
- **6** Capacitance Tolerance
- 6 Rated Voltage

- Thickness Option
- 8 Product & Plating Method
- 9 Samsung Control Code
- Reserved For Future Use
- Packaging Type

## **1** Samsung Multilayer Ceramic Capacitor

## 2 SIZE(mm)

Code	EIA CODE	Size(mm)
03	0201	0.6 × 0.3
05	0402	1.0 × 0.5
10	0603	1.6 × 0.8
21	0805	2.0 × 1.25
31	1206	3.2 × 1.6
32	1210	3.2 × 2.5
43	1812	4.5 × 3.2
55	2220	5.7 × 5.0





### **3** CAPACITANCE TEMPERATURE CHARACTERISTIC

Code	Temperature Characteristics				Temperature Range
С		COG	C△	0 ± 30 (ppm/ °C)	
Р		P2H	P△	-150±60	
R		R2H	R△	-220±60	
S	Class	S2H	S△	-330±60	-55 ~ +125℃
Т		T2H	T△	-470±60	
U		U2J	U△	-750±60	
L		S2L	S△	+350 ~ -1000	
Α		X5R	X5R	±15%	-55 ~ +85℃
В	Class II	X7R	X7R	±15%	-55 ~ +125℃
X	Ciass II	X6S	X6S	±22%	-55 ~ +105℃
F		Y5V	Y5V	+22 ~ -82%	-30 ~ +85℃

#### **\* Temperature Characteristic**

Temperature Characteristics	Below 2.0pF	2.2 ~ 3.9pF	Above 4.0pF	Above 10pF
СФ	COG	COG	C0G	C0G
Р∆	-	P2J	P2H	P2H
R∆	-	R2J	R2H	R2H
SΔ	-	S2J	S2H	S2H
TΔ	-	T2J	T2H	T2H
UΔ	-	U2J	U2J	U2J

 $J:\pm 120 PPM/{}^{\circlearrowright},\, H:\pm 60 PPM/{}^{\circlearrowleft},\, G:\pm 30 PPM/{}^{\circlearrowleft}$ 

## **4** NOMINAL CAPACITANCE

Nominal capacitance is identified by 3 digits.

The first and second digits identify the first and second significant figures of the capacitance.

The third digit identifies the multiplier. 'R' identifies a decimal point.

## Example

Code	Nominal Capacitance
1R5	1.5pF
103	10,000pF, 10nF, 0.01 μF
104	100,000pF, 100nF, 0.1 μ F





## **O CAPACITANCE TOLERANCE**

Code	Tolerance	Nominal Capacitance
Α	±0.05pF	
В	±0.1pF	
С	±0.25pF	Less than 10pF (Including 10pF)
D	± 0.5pF	(mordaling Topi )
F	±1pF	
F	±1%	
G	±2%	
J	±5%	More than 10pF
K	±10%	More than 10pF
М	±20%	
Z	+80, -20%	

# **6** RATED VOLTAGE

Code	Rated Voltage	Code	Rated Voltage
R	4.0V	D	200 V
Q	6.3V	E	250V
Р	10V	G	500 V
О	16V	Н	630 V
Α	25V	I	1,000V
L	35V	J	2,000V
В	50V	К	3,000V
С	100V		





## THICKNESS OPTION

Size	Code	Thickness(T)	Size	Code	Thickness(T)
0201(0603)	3	0.30±0.03		F	1.25±0.20
0402(1005)	5	0.50±0.05		Н	1.6±0.20
0603(1608)	8	0.80±0.10	1812(4532)	I	2.0±0.20
	Α	0.65±0.10		J	2.5±0.20
	С	0.85±0.10		L	3.2±0.30
0805(2012)	F	1.25±0.10		F	1.25±0.20
	Q	1.25±0.15		н	1.6±0.20
	Y	1.25±0.20	2220(5750)	I	2.0±0.20
	С	0.85±0.15		J	2.5±0.20
1206(3216)	F	1.25±0.15		L	3.2±0.30
	Н	1.6±0.20			
	F	1.25±0.20			
1210(3225)	Н	1.6±0.20			
	I	2.0±0.20			
	J	2.5±0.20			
	V	2.5±0.30			

## PRODUCT & PLATING METHOD

Code	Electrode	Termination	Plating Type
Α	Pd	Ag	Sn_100%
N	Ni	Cu	Sn_100%
G	Cu	Cu	Sn_100%

# SAMSUNG CONTROL CODE

Code	Description of the code	Code	Description of the code
Α	Array (2-element)	N	Normal
В	Array (4-element)	Р	Automotive
С	High - Q	L	LICC





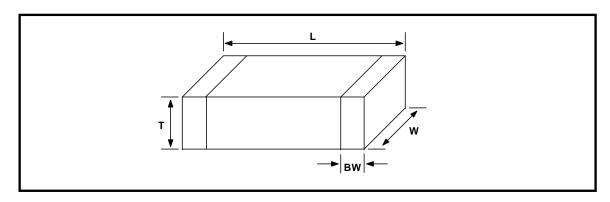
## **TRESERVED FOR FUTURE USE**

Code	Description of the code
N	Reserved for future use

## **1** PACKAGING TYPE

Code	Packaging Type	Code	Packaging Type
В	Bulk	F	Embossing 13" (10,000EA)
Р	Bulk Case	L	Paper 13" (15,000EA)
С	Paper 7"	0	Paper 10"
D	Paper 13" (10,000EA)	S	Embossing 10"
Е	Embossing 7"		

# APPEARANCE AND DIMENSION



CODE	EIA CODE	DIMENSION ( mm )							
CODE	EIA CODE	L	w	T (MAX)	BW				
03	0201	0.6 ± 0.03	0.3 ± 0.03	0.33	0.15 ± 0.05				
05	0402	1.0 ± 0.05	0.5 ± 0.05	0.55	0.2 +0.15/-0.1				
10	0603	1.6 ± 0.1	0.8 ± 0.1	0.9	0.3 ± 0.2				
21	0805	2.0 ± 0.1	1.25 ± 0.1	1.35	0.5 +0.2/-0.3				
24	4000	3.2 ± 0.15	1.6 ± 0.15	1.40	0.5 +0.2/-0.3				
31	1206	$3.2 \pm 0.2$	1.6 ± 0.2	1.8	0.5 +0.3/-0.3				
20	1210	3.2 ± 0.3	2.5 ± 0.2	2.7	0.6 ± 0.3				
32	1210	3.2 ± 0.4	2.5 ± 0.3	2.8	0.6 ± 0.3				
43	1812	4.5 ± 0.4	3.2 ± 0.3	3.5	0.8 ± 0.3				
55	2220	5.7 ± 0.4	5.0 ± 0.4	3.5	1.0 ± 0.3				





NO	ITE	М	PER	FORMANCE	TEST	CONDITION			
1	Appea	rance	No Abnormal Exterior	Appearance	Through Microscope(×10	Through Microscope(x10)			
2	Insula Resist		10,000MΩ or 500 MΩ·μF N  Rated Voltage is below 10,000MΩ or 100 MΩ·μF N	v 16V ;	Apply the Rated Voltage For 60 ~ 120 Sec.				
3	Withsta	Ü	No Dielectric Breakdov Mechanical Breakdown		Class II:250% of the Rated	Class I : 300% of the Rated Voltage for 1~5 sec.   Class II :250% of the Rated Voltage for 1~5 sec. is applied with less than $50\text{m}$ current			
					Capacitance	Frequency	Voltage		
		Class ī	Within the specifie	d tolerance	≤ 1,000 pF	1Mb ±1 0%	0.5 5 1/		
	Capacita	1			>1,000 pF	1kHz ±1 0%	0.5 ~ 5 Vrms		
4	nce				Capacitance	Frequency	Voltage		
		Class II	Within the specifi	ed tolerance	≤ 10 <i>μ</i> F	1kHz ±1 0%	1.0±0.2Vrms		
		11			>10 <i>µ</i> F	120 Hz <b>±20</b> %	0.5±0.1 Vrms		
			Capacitance ≥ 30pF :	Q ≥ 1,000	Capacitance	Frequency	Voltage		
5	Q	Class	< 30pF	: Q ≥ 400 +20C	≤ 1,000 pF	1Mb ±10%			
		I	( C	: Capacitance )	>1,000 pF	1kHz ±1 0%	0.5 ~ 5 Vrms		
			1. Characteristic : A()	(5R), B(X7R), X(X6S)	Capacitance	Frequency	Voltage		
			Rated Voltage	Spec	≤ 10 <i>μ</i> F	1 kHz ±1 0%	1.0±0.2Vrms		
			≥ 25V	0.025 max	>10 <i>µ</i> F	120 Hz ± 20%	0.5±0.1 V rms		
			16V	0.035 max					
			10V	0.05 max	-				
			6.3V	0.05 max/ 0.10max*1	*1. 0201 C≥0.022uF, 0				
			2. Characteristic : F(	/5V)	1812 C≥47uF, 2220 All Low Profile Capa				
6	Tan δ	Class	Rated Voltage	Spec	*2 0603 C≥0.47uF, 08 *3. 0402 C≥0.033uF, 06				
		П	50V	0.05 max, 0.07max*2	All 0805, 1206 size		_		
			35V	0.07 max	*4 1210 C>6.8uF	, 1210 C → 0.8u			
			25V	0.05 max/ 0.07 max* <sup>3</sup> / 0.09max* <sup>4</sup>	*5 0402 C≥0.22uF				
			16V	0.09 max/ 0.125max*5	*6 All 1812 size				
			10V	0.125 max/ 0.16max*6					
			6.3V	0.16max	]				





NO	ITEM PERFORMANCE						TEST CONDITION		
NO	IIE	<b>VI</b> 		PERFOR	MANCE		TEST CONDITION		
						'	shall be measured by the steps		
			Characte	rictice	Temp. Coefficient	shown in the	following table.		
			Cilaiacie	:1151105	(PPM/℃)	Step	Temp.(℃)		
			COC	3	0 ± 30	1	25 ± 2		
		Class	PH	ļ .	-150 ± 60	2	Min. operating temp. $\pm$ 2		
		I	RH	l	-220 ± 60	3	25 ± 2		
			SH	l	-330 ± 60	4	Max. operating temp $\pm$ 2		
			ТН		-470 ± 60	5	25 ± 2		
			UL		-750 ± 120	(1) Class I	20 – 2		
			SL		+350 ~ -1000	` '	Coefficient shall be calculated from		
	Temperature					the formula a			
7	Characteristics of Capacitance						$nt = \frac{C2 - C1}{C1 \times \triangle T} \times 10^6 \text{ [ppm/°C]}$		
	or Capacitanio					C1; Capacita	ance at step 3		
			Characteristics Capacitance Characteristics		Capacitance Change	C2: Capacita			
					with No Bias	△T: 60°C(=8	35 (-25 ()		
		Class Ⅱ	A(X5 B(X7		± 15%	(2) CLASS II			
			X(X6	SS)	± 22%	Capacitance (	Change shall be calculated from the		
			F(Y5	5V)	+22% ~ -82%	formula as be			
							C1 × 100(%)		
						C1; Capacita	ance at step 3		
						C2: Capacita	ance at step 2 or 4		
						Apply 500g.f	* Pressure for 10±1 sec.		
						* 200g.f for 0201 case size.			
	Adhaaire	Ctronath	No Indicati	ion Of Dool	ling Shall Occur On The				
8	Adhesive of Termi	•	No Indication Of Peeling Shall Occur On The Terminal Electrode.				500g.f		
		An	No	minel !-	oogo oboli	Bending limit	; 1mm		
		Apperance	No mecha	anicai dam	nage shall occur.	Test speed ;	1.0mm/SEC.		
			Charac	teristics	Capacitance Change	Keep the test	board at the limit point in 5 sec., e capacitance.		
					Within $\pm$ 5% or $\pm$ 0.				
			Clas	ss I	5 pF whichever is		.20		
	Bending				larger		( R=230		
9	9 Strength			A(X5R)/		50			
		Capacitance		B(X7R)/	Within ± 12.5%		<u> </u>		
				X(X6S)	12.070		<u> </u>		
				- 1,1100)		<b>│                                    </b>	Bending limit		
			Class II			45±1	45±1		
				F(Y5V)	Within ± 30%				
				` ′					





NO	ın	ΓEM		PERF	ORMANCE		TEST CONDITION			
			More Than	n 75% of th	e terminal surface is to	Solder	Sn-3Ag-0.5	Cu 63Sn-37Pb		
				d newly, So or dissolve	o metal part does not	Solder Temp.	245±5℃	235±5℃		
10	Solde	erability			7/	Flux	R	MA Type		
			<b> →</b> // // <del> </del>			Dip Tim	e 3±0.3 sec	5±0.5 sec.		
						Pre-heatir	ng at 80~120	℃ for 10~30 sec.		
		Apperance	No mecha	anical dam	age shall occur.	Solder Te	mperature: 270	±5℃		
			Charac	teristics	Capacitance Change	Dip Time	: 10±1 sec.			
				_	Within ±2.5% or			fully immersed and		
			Clas	ss I	±0.25 pF whichever is	preheated as below :				
		Capacitance		A(X5R)/	larger	STEP	TEMP.(℃)	TIME(SEC.)		
				B(X7R)	Within ±7.5%	1	80~100	60		
			Class II	X(X6S)	Within ±15%	2	150~180	60		
	Resistance to			F	Within ±20%	Leave the	capacitor in an	nbient condition for		
11	Soldering heat	Q (Class I)	Capacitar	$0.00 \ge 30 \mathrm{pF}$	: Q≥ 1000 : Q≥ 400+20xC (C: Capacitance)	specified time* before measurement  * 24 ± 2 hours (Class I)  24 ± 2 hours (Class II)				
		Tan $\delta$ (Class ${\mathbb I}$ )	Within the	e specified	initial value					
		Insulation Resistance	Within the	e specified	initial value					
		Withstanding Voltage	Within the	e specified	initial value					
		Appearance	No mecha	anical dam	age shall occur.					
			Charact	teristics	Capacitance Change					
			Clas	s I	Within ±2.5% or ±0.25 pF whichever is larger	The capacitor shall be subjected to a Harmonic Motion having a total amplitude of 1.5mm changing frequency from 10Hz to 55				
	Vibration	Capacitance	Class	A(X5R)/ B(X7R)	Within ±5%		to 10Hz In 1 m			
12	Test		П	X(X6S)	Within ±10%	· '	s for 2nours ea llar directions	ch in 3 mutually		
				F(Y5V)	Within ±20%	porporidio	nar anochorio			
		Q (Class I)	Within the	e specified	initial value					
		Tan $\delta$ (Class ${\mathbb I}$ )	Within the	e specified	initial value					
		Insulation Resistance	Within the	e specified	initial value					





NO	ITE	M		PERFO	RMANCE	TEST CONDITION				
		Appearance	No mechanic	cal damage sha	Il occur.	Temperature : 40±2 ℃				
				cteristics	Capacitance Change	Relative humidity : 90~95 %RH				
					Within ±5.0% or ±0.5pF	Duration time : 500 +12/-0 hr.				
			Class I		whichever is larger	Leave the capacitor in ambient				
		Capacitance		A(X5R)/	M/H-i 40 50/	condition for specified time* before				
			Class	B(X7R)/ X(X6S)	Within ±12.5%	measurement.				
				F(Y5V)	Within ±30%	CLASSI : 24±2 Hr. CLASSII : 24±2 Hr.				
		Q	Capacitance	≥ 30pF : Q≥	350	027.002 1 21.22 1				
	Humidity	CLASSI	10≤ Capacit	tance <30 $\mathrm{pF}$ : $\mathrm{C}$	Q≥ 275 + 2.5×C					
13	(Steady	CLASSI	Capacitance	< 10pF : Q≥ 2	200 + 10×C (C: Capacitance)					
	State)		Characteri	stic: A(X5R),	2. Characteristic : F(Y5V)					
			B(X7R) 0.05max (16V and over)							
					0.075max (25V and over)					
		Tan $\delta$	0.075max (10	OV)	0.1max (16V, C<1.0μF)					
		CLASS II	0.075max		0.125max(16V, C≥ 1.0 $\mu$ F)					
			(6.3V excep	ot Table 1)	0.15max (10V)					
			0.125max*		0.195max (6.3V)					
			(refer to Tab	le 1)						
		Insulation Resistance	1,000 MΩ or	50MΩ·μF whichev	ver is smaller.					
		Appearance	No mechanic	cal damage sha	Il occur.	Applied Voltage: rated voltage				
				cteristics	Capacitance Change	Temperature: 40±2 °C				
		Capacitance	0.10.10		-	Humidity::90~95%RH				
			Clas		Within ±5.0% or ±0.5pF	Duration Time : 500 +12/-0 Hr.				
				I	whichever is larger	Charge/Discharge Current : 50mA max.				
				A(X5R)/	Within ±12.5%	Perform the initial measurement according to				
				B(X7R)/	Within ±12.5%	Note1.				
			Class II	X(X6S)	Within ±30%					
			Class II		Within ±30%					
				F(Y5V)	Within ±30%	Perform the final measurement according to Note2.				
	Moisture	Q	Capacitance	≥30pF : Q≥ 2	200					
14	Resistance	(Class I)	Capacitance	<30 pF : Q≥ 10	00 + 10/3×C (C: Capacitance)					
			1. Characteri	stic : A(X5R),	2. Characteristic : F(Y5V)					
				B(X7R)						
			0.05max (16\	V and over)	0.075max (25V and over)					
			0.075max (10	OV)	0.1max (16V, C<1.0μ <sup>Γ</sup> )					
		Tan δ	0.075max		0.125max(16V, C≥ 1.0μF)					
		(Class II)	(6.3V excep	t Table 1)	0.15max (10V)					
		(01400 11)	0.125max*		0.195max (6.3V)					
			(refer to Tal	ble 1)						
			X(X6S) 0.11r	max (6.3V and I	pelow)					
		Insulation Resistance	500 MΩ or 25	5MΩ·μF whicheve	r is smaller.					
		resistance								





NO	ITE	М		PERI	FORMANCE		TEST CONDIT	ION	
		Appearance	No mechanio	cal damage	shall occur.	1	oltage: 200%* of the	<del>-</del>	
			Charact	eristics	Capacitance Change		Temperature: max. operating temperature  Duration Time: 1000 +48/-0 Hr.		
			Class	; I	Within ±3% or ±0.3pF, Whichever is larger	Charge/Discharge Current : 50m/ max.			
		Capacitance		A(X5R)/ B(X7R)	Within ±12.5%	* refer to voltage	table(3): 150%/1009	% of the rated	
			Class Ⅱ	X(X6S)	Within ±25%	Perform th	e initial measurement	according to	
				E0 (E) 0	Within ±30%	Note1 for	Class II		
				F(Y5V)	Within ±30%				
		Q	Capacitance 10≤ Capaci	-	$Q \ge 350$ F: $Q \ge 275 + 2.5xC$	Perform th	e final measurement	according to	
		(Class I)			≥ 200 +10×C (C: Capacitance)	Note2.			
15	High		Characteristic : A(X5R), 2. Characteristic : F(Y5V)						
15 Temperature Resistance		Tan δ (Class Ⅱ)  Insulation Resistance	0.05max (16V and o 0.075max (10 0.075max (6.3V excep 0.125max* (refer to Ta	ov)  that Table 1)  ble 1)  max (6.3V a	0.075max (25V and over) 0.1max(16V, C<1.0/  0.125max(16V, C≥1.0/  0.15max (10V) 0.195max (6.3V)				
		Appearance	No mechanio	cal damage	shall occur.	Capacitor	shall be subjected	d to 5 cycles.	
			Charact	eristics	Capacitance Change	Condition	for 1 cycle :		
			Class	· T	Within ±2.5% or ±0.25 pF	Step	Temp.(℃)	Time(min.)	
			Glasc	, -	Whichever is larger	1	Min. operating	30	
		Capacitance	Class	A(X5R)/ B(X7R)/	Within ±7.5%	2	temp.+0/-3 25	2~3	
46	Temperature			X(X6S)	Within ±15%		Max. operating		
16 Cycle				F(Y5V)	Within ±20%	3	temp.+3/-0	30	
		Q	Within the s	pecified initia	al value	4 25 2-3			
		(Class I)				-	e capacitor in amb		
		Tan $\delta$ (Class $II$ )	Within the s	pecified initia	al value	for specified time* before measurement  * 24 ± 2 hours (Class I)			
		Insulation Resistance	Within the sp	pecified initia	al value	$24 \pm 2 \text{ hours (Class II)}$ $24 \pm 2 \text{ hours (Class II)}$			





		Reco	ommended Sold	ering Method		
		Size	Temperature		Cond	lition
		inch (mm)	Characteristic	Capacitance	Flow	Reflow
		0201 (0603)	-	-	-	0
		0402 (1005)				
			Class I	-	0	0
		0603 (1608)	Class II	$C < 1\mu F$	0	0
			Class II	$C \geq 1\mu$ F	-	0
	Recommended	0805 (2012)	Class I	-	0	0
18	Soldering Method		Class II	C < 4.7μF	0	0
	By Size & Capacitance		Class II	$C \geq 4.7 \mu F$	•	0
	2, 0.20 d oupdona		Array	-	-	0
			Class I	-	0	0
		1206 (3216)	Class II	C < 10μF	0	0
		1200 (3210)	Class II	$C \geq 10 \mu F$	-	0
			Array	-	-	0
		1210 (3225)				0
		1808 (4520)			_	0
		1812 (4532)	-	-	-	0
		2220 (5750)				0

Note1. Initial Measurement For Class  $\ensuremath{\mathbb{I}}$ 

Perform the heat treatment at 150%+0/-10% for 1 hour. Then Leave the capacitor in ambient condition for  $48\pm4$  hours before measurement. Then perform the measurement.

#### Note2. Latter Measurement

#### 1. CLASS I

Leave the capacitor in ambient condition for 24±2 hours before measurement

Then perform the measurement.

#### 2. Class ${\mathbb I}$

Perform the heat treatment at  $150\,^{\circ}\text{C} + 0/-10\,^{\circ}\text{C}$  for 1 hour. Then Leave the capacitor in ambient condition for  $48\pm4$  hours before measurement. Then perform the measurement.

\*Table1.

Tan ∂	0.125max*
Tan ∂  Class ∏ A(X5R), B(X7R)	$0.125 \text{max}^*$ $0201 \text{ C} \ge 0.022 \mu\text{F}$ $0402 \text{ C} \ge 0.22 \mu\text{F}$ $0603 \text{ C} \ge 2.2 \mu\text{F}$ $0805 \text{ C} \ge 4.7 \mu\text{F}$ $1206 \text{ C} \ge 10.0 \mu\text{F}$ $1210 \text{ C} \ge 22.0 \mu\text{F}$ $1812 \text{ C} \ge 47.0 \mu\text{F}$ $2220 \text{ C} \ge 100.0 \mu\text{F}$
	All Low Profile
	All Low Profile
	Capacitors (P.16).
	- Capacito (* .10).

\*Table2.

perature Resistance test					
± 30%					
0402 C ≥ 0.47 <i>μ</i> F					
0603 C ≥ 2.2μF					
0805 C ≥ $4.7\mu$ F					
1206 C ≥ 10.0 <i>μ</i> F					
1210 C ≥ 22.0 <i>μ</i> F					
1812 C ≥ 47.0 <i>μ</i> F					
2220 C ≥ 100.0 $\mu$ F					

\*Table3.

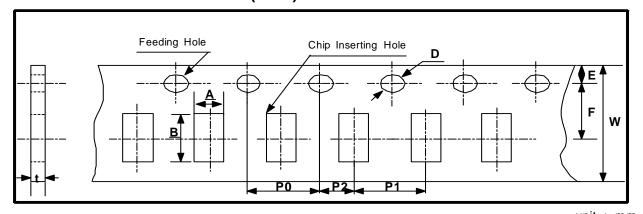
High Temperature Resistance test								
Applied Voltage	100% of the rated voltage	150% of the rated voltage						
Class II A(X5R), B(X7R), X(X6S), F(Y5V)	0201 C $\geq 0.1 \mu F$ 0402 C $\geq 1.0 \mu F$ 0603 C $\geq 4.7 \mu F$ 0805 C $\geq 22.0 \mu F$ 1206 C $\geq 47.0 \mu F$ 1210 C $\geq 100.0 \mu F$ All Low Profile Capacitors (P.16).	0201 C $\geq 0.022 \mu F$ 0402 C $\geq 0.47 \mu F$ 0603 C $\geq 2.2 \mu F$ 0805 C $\geq 4.7 \mu F$ 1206 C $\geq 10.0 \mu F$ 1210 C $\geq 22.0 \mu F$ 1812 C $\geq 47.0 \mu F$ 2220 C $\geq 100.0 \mu F$						





# **PACKAGING**

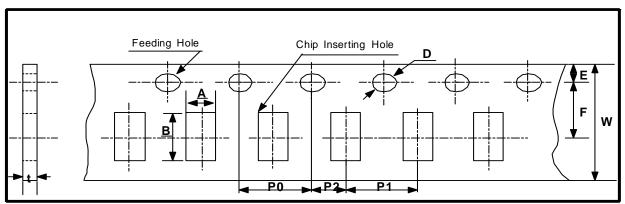
# ● CARDBOARD PAPER TAPE (4mm)



unit : mm

	mbol ype	Α	В	w	F	E	P1	P2	P0	D	t
D i m	0603 (1608)	1.1 ±0.2	1.9 ±0.2								
e n s	0805 (2012)	1.6 ±0.2	2.4 ±0.2	8.0 ±0.3	3.5 ±0.05	1.75 ±0.1	4.0 ±0.1	2.0 ±0.05	4.0 ±0.1	Ф1.5 +0.1/-0	1.1 Below
i o n	1206 (3216)	2.0 ±0.2	3.6 ±0.2								

## ● CARDBOARD PAPER TAPE (2mm)



unit: mm

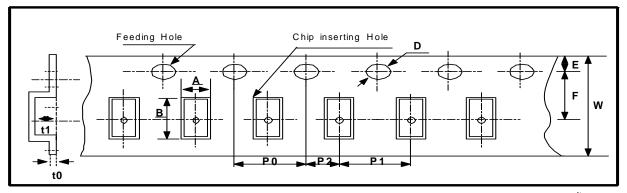
	ymbol Type	Α	В	w	F	E	P1	P2	P0	D	t
D i m e	0201 (0603)	0.38 ±0.03	0.68 ±0.03	8.0	3.5	1.75	2.0	2.0	4.0	Ф1.5	0.37 ±0.03
n s i o n	0402 (1005)	0.62 ±0.04	1.12 ±0.04	±0.3	±0.05	±0.1	±0.05	±0.05	±0.1	+0.1/-0.03	0.6 ±0.05





# **PACKAGING**

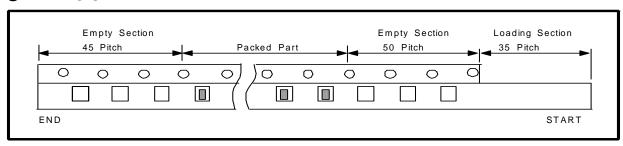
### **● EMBOSSED PLASTIC TAPE**



unit: mm

Sy	m bol	Α	В	w	F	Е	P1	P2	P0	D	t1	t0
Т	уре	, ,				_						
	0805 (2012)	1.45 ±0.2	2.3 ±0.2									
P	1206 (3216)	1.9 ±0.2	3.5 ±0.2	8.0 ±0.3	3.5 ±0.05		4.0 ±0.1				2.5 max	
m e	1210 (3225)	2.9 ±0.2	3.7 ±0.2			1.75		2.0	4.0	Ф1.5 +0.1/-0		0.6
n s i	1808 (4520)	2.3 ±0.2	4.9 ±0.2			±0.1		±0.05	±0.1	+0.17-0		Below
o n	1812 (4532)	3.6 ±0.2	4.9 ±0.2	12.0 ±0.3	5.60 ±0.05		8.0 ±0.1				3.8 max	
	2220 (5750)	5.5 ±0.2	6.2 ±0.2									

### **TAPING SIZE**



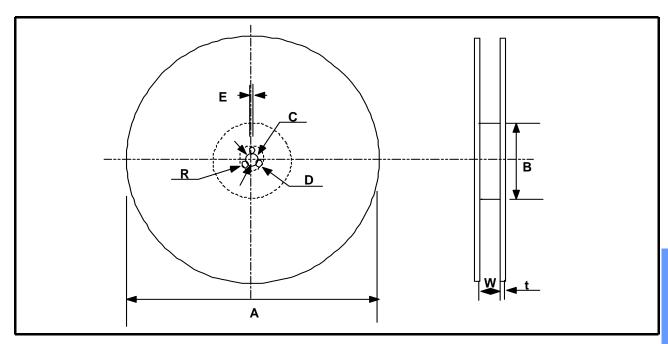
Type	Symbol	Size	Cardboard Paper Tape	Symbol	Size	Embossed Plastic Tape
		0201(0603)	10,000		All Size ≤3216 1210(3225),1808(4520) (t≤1.6mm)	2,000
7" Reel	С	0402(1005)	10,000	E	1210(3225)(t≥2.0mm)	1,000
		OTHERS	4,000		1808(4520)(t≥2.0mm)	1,000
10" Reel	0	-	10,000	-	-	-
	D	0402(1005)	50,000		All Size ≤3216 1210(3225),1808(4520) (t<1.6mm)	10,000
		OTHERS	10,000		$1210(3225)(1.6 \le t < 2.0 \text{ m m})$ $1206(3216)(1.6 \le t)$	8,000
13" Reel		0603(1608)	10,000 or 15,000	F	$1210(3225),1808(4520) $ $(t \ge 2.0 \text{mm})$	4,000
	L	L 0805(2012) 15,000 or (t≤0.85mm) 10,000(Option)		1812(4532)(t≤2.0mm)	4,000	
		1206(3216) (t≤0.85mm)	10,000		1812(4532)(t>2.0mm) 5750(2220)	2,000





# **PACKAGING**

## • REEL DIMENSION



unit: mm

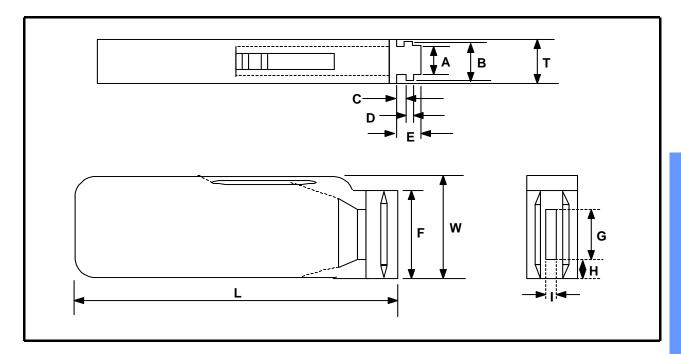
Symbol	Α	В	С	D	E	W	t	R
7" Reel	ф180+0/ -3	ф60+1/ -3	442   0.2	25   0.5	20105	0.14.5	1.2±0.2	4.0
13" Reel	ф330±2.0	φ80+1/ -3	φ13±0.3	25±0.5	2.0±0.5	9±1.5	2.2±0.2	1.0





### BULK CASE PACKAGING

- Bulk case packaging can reduce the stock space and transportation costs.
- The bulk feeding system can increase the productivity.
- It can eliminate the components loss.



unit: mm

Symbol	Α	В	Т	С	D	E
Dimension	6.8±0.1	8.8±0.1	12±0.1	1.5+0.1/-0	2+0/-0.1	3.0+0.2/-0

Symbol	F	W	G	Н	L	I
Dimension	31.5+0.2/-0	36+0/-0.2	19±0.35	7±0.35	110±0.7	5±0.35

### QUANTITY OF BULK CASE PACKAGING

unit : pcs

0:	0402(4005)	0002(4000)	0805(	2012)
Size	0402(1005)	0603(1608)	T=0.65mm	T=0.85mm
Quantity	50,000	10,000 or 15,000	10,000	5,000 or 10,000

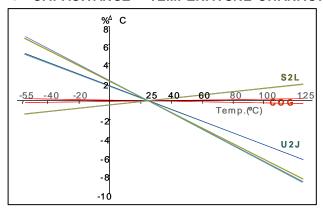


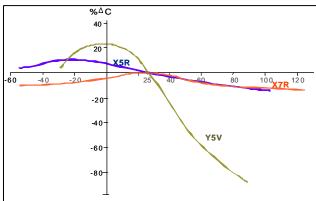


## **APPLICATION MANUAL**

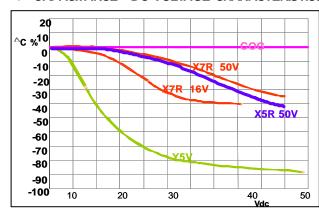
#### • ELECTRICAL CHARACTERISTICS

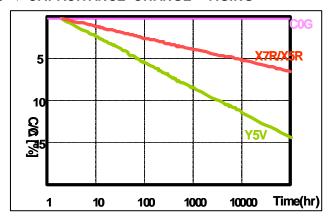
#### ► CAPACITANCE - TEMPERATURE CHARACTERISTICS



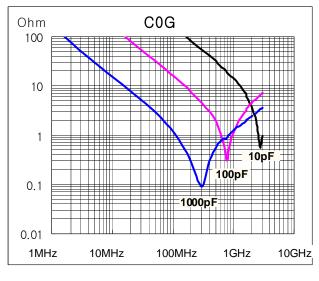


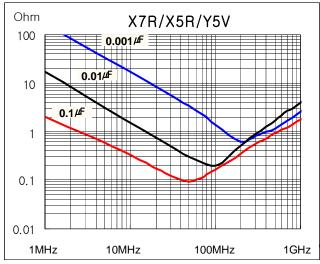
#### ► CAPACITANCE - DC VOLTAGE CHARACTERISTICS ► CAPACITANCE CHANGE - AGING





#### ► IMPEDANCE - FREQUENCY CHARACTERISTICS









#### STORAGE CONDITION

#### ▶ Storage Environment

The electrical characteristics of MLCCs were degraded by the environment of high temperature or humidity. Therefore, the MLCCs shall be stored in the ambient temperature and the relative humidity of less than 40°C and 70%, respectively.

Guaranteed storage period is within 6 months from the outgoing date of delivery.

#### ▶ Corrosive Gases

Since the solderability of the end termination in MLCC was degraded by a chemical atmosphere such as chlorine, acid or sulfide gases, MLCCs must be avoid from these gases.

#### ▶ Temperature Fluctuations

Since dew condensation may occur by the differences in temperature when the MLCCs are taken out of storage, it is important to maintain the temperature-controlled environment.

#### DESIGN OF LAND PATTERN

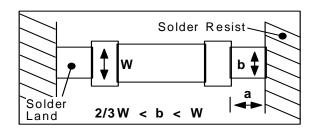
When designing printed circuit boards, the shape and size of the lands must allow for the proper amount of solder on the capacitor.

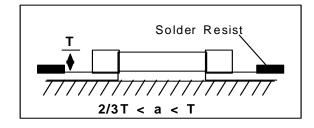
The amount of solder at the end terminations has a direct effect on the crack.

The crack in MLCC will be easily occurred by the tensile stress which was due to too much amount of solder. In contrast, if too little solder is applied, the termination strength will be insufficiently.

Use the following illustrations as guidelines for proper land design.

Recommendation of Land Shape and Size.









#### ADHESIVES

When flow soldering the MLCCs, apply the adhesive in accordance with the following conditions.

#### ► Requirements for Adhesives

They must have enough adhesion, so that, the chips will not fall off or move during the handling of the circuit board.

They must maintain their adhesive strength when exposed to soldering temperature.

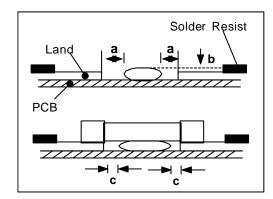
They should not spread or run when applied to the circuit board.

They should harden quickly. They should not corrode the circuit board or chip material.

They should be a good insulator. They should be non-toxic, and not produce harmful gases, nor be harmful when touched.

#### ▶ Application Method

It is important to use the proper amount of adhesive. Too little and much adhesive will cause poor adhesion and overflow into the land, respectively.



		unit : mm
Туре	21	31
а	0.2 min	0.2 min
b	70~100 H	70~100 <i>⊭</i> ™
С	> 0	> 0

#### Adhesive hardening Characteristics

To prevent oxidation of the terminations, the adhesive must harden at 160 ℃ or less, within 2 minutes or less.

#### MOUNTING

#### Mounting Head Pressure

Excessive pressure will cause crack to MLCCs. The pressure of nozzle will be 300g maximum during mounting.

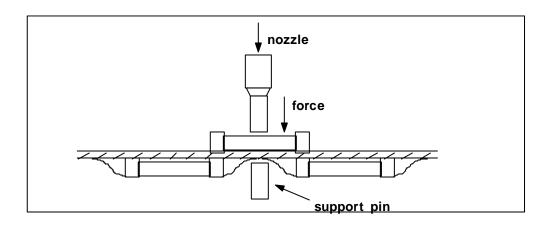




## ▶ Bending Stress

When double-sided circuit boards are used, MLCCs first are mounted and soldered onto one side of the board. When the MLCCs are mounted onto the other side,

it is important to support the board as shown in the illustration. If the circuit board is not supported, the crack occur to the ready-installed MLCCs by the bending stress.



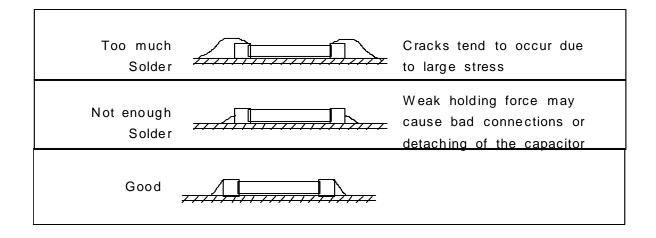
#### Manual Soldering

Manual soldering can pose a great risk of creating thermal cracks in chip capacitors.

The hot soldering iron tip comes into direct contact with the end terminations, and operator's carelessness may cause the tip of the soldering iron to come into direct contact with the ceramic body of the capacitor.

Therefore the soldering iron must be handled carefully, and close attention must be paid to the selection of the soldering iron tip and to temperature control of the tip.

#### Amount of Solder







### ▶ Cooling

Natural cooling using air is recommended. If the chips are dipped into solvent for cleaning, the temperature difference( $\triangle T$ ) must be less than 100  $^{\circ}$ C

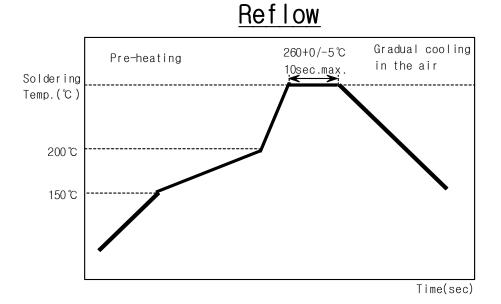
#### ▶ Cleaning

If rosin flux is used, cleaning usually is unnecessary. When strongly activated flux is used, chlorine in the flux may dissolve into some types of cleaning fluids, thereby affecting the chip capacitors. This means that the cleaning fluid must be carefully selected, and should always be new.

### ▶ Notes for Separating Multiple, Shared PC Boards.

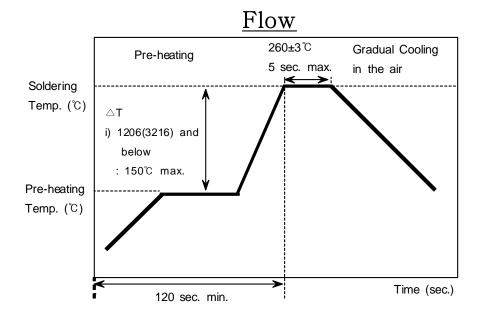
A multi-PC board is separated into many individual circuit boards after soldering has been completed. If the board is bent or distorted at the time of separation, cracks may occur in the chip capacitors. Carefully choose a separation method that minimizes the bending often circuit board.

## ▶ Recommended Soldering Profile









# Soldering Iron

Variation of Temp.	Soldering	Pre-heating	Soldering	Cooling
	Temp (°C)	Time (Sec)	Time(Sec)	Time(Sec)
△T≤130	300±10℃max	≥ 60	≤ 4	-

Condition of Iron facilities					
Wattage	Tip Diameter	Soldering Time			
20W Max	3mm Max	4 Sec Max			

<sup>\*</sup> Caution - Iron Tip Should Not Contact With Ceramic Body Directly.

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